

<b>Notice of References Cited</b>	Application/Control No. 10/659,307		Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Cong-Lac Huynh		Art Unit 2178	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0023436 A1	09-2001	SRINIVASAN et al.	709/219
*	B	US-2003/0140159 A1	07-2003	Campbell et al.	709/231
*	C	US-2004/0216173 A1	10-2004	Horoszowski et al.	725/145
*	D	US-2004/0221323 A1	11-2004	Watt, James H.	725/135
*	E	US-2004/0221227 A1	11-2004	Wu, Peng	715/512
*	F	US-2007/0118794 A1	05-2007	Hollander et al.	715/512
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.